

Notice of References Cited	Application/Control No. 10/053,278	Applicant(s)/Patent Under Reexamination BYUN ET AL.	
	Examiner Kiley Stoner	Art Unit 1725	Page 1 of 1

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	U	US 2002/0104874A1 Byun et al. (8-8-02).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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